Search Notes				

Application/Control No.	Applicant(s)/Patent unde Reexamination	r
10/782,530	MURANAKA ET AL.	
Examiner	Art Unit	
Robert W. Wilson	2619	

SEARCHED				
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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Refer to	print out	1/24/08	KAN

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
·	DATE	EXMR		
Discussed allowability with C: Nguyen	1/24/2008	RWW		
370/389, 470, 474 (Text)	1/24/2008	RWW		
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